



## SILICON N-P-N HIGH-VOLTAGE TRANSISTORS

N-P-N high-voltage small-signal transistors for general purposes and especially telephony applications and encapsulated in a TO-92 envelope.

P-N-P complements are 2N5400 and 2N5401.

### QUICK REFERENCE DATA

		2N5550	2N5551	
Collector-base voltage (open emitter)	$V_{CB0}$	max. 160	180	V
Collector-emitter voltage (open base)	$V_{CEO}$	max. 140	160	V
Collector current	$I_C$	max. 600	600	mA
Total power dissipation up to $T_{amb} = 25\text{ }^\circ\text{C}$	$P_{tot}$	max. 500	500	mW
Junction temperature	$T_j$	max. 150	150	$^\circ\text{C}$
Collector-emitter saturation voltage $I_C = 50\text{ mA}; I_B = 5\text{ mA}$	$V_{CEsat}$	max. 0,25	0,20	V
D.C. current gain $I_C = 10\text{ mA}; V_{CE} = 5\text{ V}$	$h_{FE}$	min. 60	80	

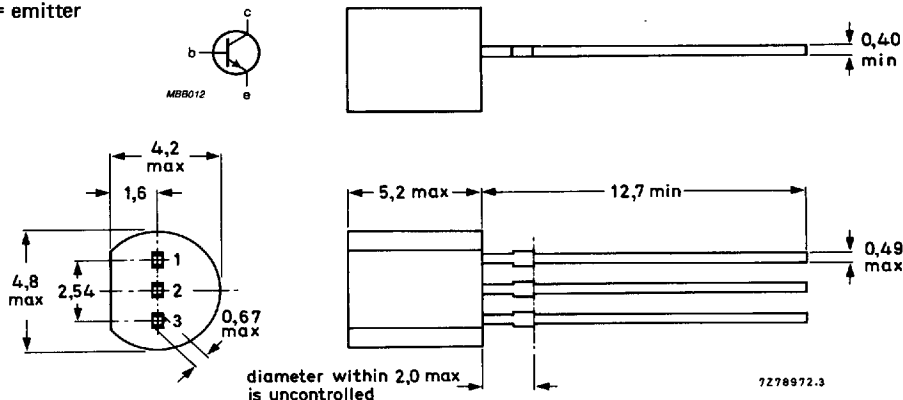
### MECHANICAL DATA

Dimensions in mm

Fig. 1 TO-92.

#### Pinning

- 1 = collector
- 2 = base
- 3 = emitter



Capability approved to CECC NECC-C-002

2N5550  
2N5551

**RATINGS**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

			2N5550	2N5551	
Collector-base voltage (open emitter)	$V_{CBO}$	max.	160	180	V
Collector-emitter voltage (open base)	$V_{CEO}$	max.	140	160	V
Emitter-base voltage (open collector)	$V_{EBO}$	max.	6		V
Collector current	$I_C$	max.	600		mA
Total power dissipation up to $T_{amb} = 25^\circ C$	$P_{tot}$	max.	500		mW
Junction temperature	$T_j$	max.	150		$^\circ C$
Storage temperature range	$T_{stg}$		-65 to + 150		$^\circ C$

**THERMAL RESISTANCE**

From junction to ambient	$R_{thj-a}$	max.	250		K/W
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**CHARACTERISTICS**

$T_{amb} = 25^\circ C$  unless otherwise specified

			2N5550	2N5551	
Collector cut-off current					
$I_E = 0; V_{CB} = 100 V$	$I_{CBO}$	max.	100		nA
$I_E = 0; V_{CB} = 120 V$	$I_{CBO}$	max.		50	nA
$I_E = 0; V_{CB} = 100 V; T_{amb} = 100^\circ C$	$I_{CBO}$	max.	100		$\mu A$
$I_E = 0; V_{CB} = 120 V; T_{amb} = 100^\circ C$	$I_{CBO}$	max.		50	$\mu A$
Emitter cut-off current					
$I_C = 0; V_{EB} = 4,0 V$	$I_{EBO}$	max.	50	50	nA
Breakdown voltages					
$I_C = 1,0 mA; I_B = 0$	$V_{(BR)CEO}$	min.	140	160	V
$I_C = 100 \mu A; I_E = 0$	$V_{(BR)CBO}$	min.	160	180	V
$I_C = 0; I_E = 10 \mu A$	$V_{(BR)EBO}$	min.	6,0	6,0	V
Saturation voltages					
$I_C = 10 mA; I_B = 1,0 mA$	$V_{CEsat}$	max.	0,15	0,15	V
	$V_{BEsat}$	max.	1,0	1,0	V
$I_C = 50 mA; I_B = 5,0 mA$	$V_{CEsat}$	max.	0,25	0,20	V
	$V_{BEsat}$	max.	1,2	1,0	V
D.C. current gain					
$I_C = 1,0 mA; V_{CE} = 5 V$	$h_{FE}$	min.	60	80	
$I_C = 10 mA; V_{CE} = 5 V$	$h_{FE}$	min.	60	80	
	$h_{FE}$	max.	250	250	
$I_C = 50 mA; V_{CE} = 5 V$	$h_{FE}$	min.	20	30	
Small-signal current gain					
$I_C = 1,0 mA; V_{CE} = 10 V; f = 1 kHz$	$h_{fe}$	min.	50	50	
		max.	200	200	
Output capacitance at $f = 1 MHz$					
$I_E = 0; V_{CB} = 10 V$	$C_o$	max.	6	6	pF
Input capacitance at $f = 1 MHz$					
$I_C = 0; V_{EB} = 0,5 V$	$C_i$	max.	30	30	pF

Silicon N-P-N high-voltage transistors

2N5550

2N5551

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Transition frequency at $f = 100$ MHz $I_C = 10$ mA; $V_{CE} = 10$ V	$f_T$	min.	100	100	MHz
		max.	300	300	MHz
Noise figure at $R_S = 1$ k $\Omega$ $I_C = 250$ $\mu$ A; $V_{CE} = 5$ V; $f = 10$ Hz to 15,7 kHz	F	max.	10	8	dB